

Search Notes

Application/Control No.

10/047,065

Examiner

Peter Coughlan

Applicant(s)/Patent under
Reexamination

SAITO ET AL.

Art Unit

2129

SEARCHED

Class	Subclass	Date	Examiner
706	1	6/1/2006	PDC
706	15	6/1/2006	PDC
706	45	6/1/2006	PDC
700	1	6/1/2006	PDC
700	90	6/1/2006	PDC
705	10	6/1/2006	PDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East--wavelet, market(s), analysis, trends, rate of change, correlation factor, base functions	6/1/2006	PDC
IEEE--wavelet, market(s), analysis, trends, rate of change, correlation factor, base functions	6/1/2006	PDC
Google--Yoshifuru Saito, Yoshihiro Takasuka, Yoshikazu Ishii, wavelet, market(s), rate of change	6/1/2006	PDC
Inventors--Yoshifuru Saito, Yoshihiro Takasuka, Yoshikazu Ishii	6/1/2006	PDC